

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. <b>242919US0</b>		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yuji YOSHIKAWA, et al.			
				FILING DATE Herewith		GROUP	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
MF	AA	6-11601,	01/21/94	Japan (with English Abstract)	/	X	
MF	AB	7-60856 -	03/07/95	Japan (with English Abstract)		X	
MF	AC	2000-284235	10/13/00	Japan (with English Abstract)		X	
MF	AD	2001-293813	10/23/01	Japan (with English Abstract)		X	
MF	AE	3031571	02/10/00	Japan (with English Abstract)		X	
MF	AF	2000-204301	07/25/00	Japan (with English Abstract)		X	
MF	AG	2000-6402	01/11/00	Japan (with English Abstract)		X	
MF	AH	2000-47004	02/18/00	Japan (with English Abstract)		X	
MF	AI	2000-143924	05/26/00	Japan (with English Abstract)		X	
MF	AJ	2000-266908	09/29/00	Japan (with English Abstract)		X	
MF	AK	2000-329903	11/30/00	Japan (with English Abstract)		X	
MF	AL	2001-164117	06/19/01	Japan (with English Abstract)		X	
MF	AM	2800258	07/10/98	Japan		X	
MF	AN	10-147740	06/02/98	Japan (with English Abstract)		X	
MF	AO	8-313704	11/29/96	Japan (with English Abstract)		X	
MF	AP	2001-264508	09/26/01	Japan (with English Abstract)		X	
MF	AQ	2002-22905	01/23/02	Japan (with English Abstract)		X	
MF	AR	2002-53804	02/19/02	Japan (with English Abstract)		X	
MF	AS	2002-53805	02/19/02	Japan (with English Abstract)		X	
MF	AT	2002-69426	03/08/02	Japan (with English Abstract)		X	
MF	AU	2001-316604	11/16/01	Japan (with English Abstract)		X	
MF	AV	2001-31891	02/06/01	Japan (with English Abstract)		X	
MF	AW	2000-79600	03/21/00	Japan (with English Abstract)		X	
MF	AX	2001-163906	06/19/01	Japan (with English Abstract)		X	
MF	AY	2000-17099	01/18/00	Japan (with English Abstract)		X	
MF	AZ	2001-233611	08/28/01	Japan (with English Abstract)		X	
MF	BA	2002-79616	03/19/02	Japan (with English Abstract)		X	
MF	BB	9-227169	09/02/97	Japan (with English Abstract)		X	
MF	BC	3225859	08/31/01	Japan (with English Abstract)		X	
MF	BD	2001-315285	11/13/01	Japan (with English Abstract)		X	
	BE				<input type="checkbox"/> Additional References sheet(s) attached		
Examiner <i>Wahlberg</i>					Date Considered <i>11/22/05</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 242919US0		SERIAL NO. 10/668,361	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yuji YOSHIKAWA, et al.			
				FILING DATE September 24, 2003		GROUP 1772	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
MF	AA	2001/0031317 A1	10/18/2001	H. HASEGAWA, et al.	/	/	/
MF	AB	5,874,801	02/23/1999	T. KOBAYASHI, et al.	/	/	/
	AC						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
MF	AO	1 022 587	07/26/2000	EUROPE	/	/	/
MF	AP	1 089 093	04/04/2001	EUROPE	/	/	/
MF	AQ	0 778 476	06/11/1997	EUROPE	/	/	/
MF	AR	1 279 443	01/29/2003	EUROPE	/	/	/
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <i>[Signature]</i>					Date Considered 11/23/06		
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